IN THE CLAIMS

Please amend the claims as follows:

1. (Canceled)

2. (Canceled)

3. (Canceled)

4. (Canceled)

5. (Canceled)

6. (Canceled)

7. (Canceled)

8. (Canceled)

9. (Canceled)

10. (Canceled)

11. (Canceled)

12. (Canceled)

13. (Canceled)

14. (Canceled)

15. (Canceled)

16. (Previously Presented) A method for monitoring the film build thickness of workpieces on which a first film build process has been performed, comprising the steps of:

calculating a first C_{pk} of workpieces on which a first film build process has been performed;

acquiring data relating to parameters of a second film build process in which at least one of the parameters of the first film build process has been changed;

calculating a second C_{pk} of the second film build process from said acquired data; and

calculating the difference between the first C_{pk} and the second C_{pk} to ascertain the relationship between said difference and the changed parameter.

17. (Previously Presented) A method as defined in claim 16, including the step of acquiring cost data relating to said first film build process and cost data relating to said second film build process; and

generating a cost difference utilizing the first film build process and the second film build process utilizing the first C_{pk} and the second C_{pk}.

18. (Previously Presented) A method as defined in claim 16, including the step of calculating the C_{pk} of at least one of said film build processes from range values of the film build thickness of the corresponding film build process.

19. (Previously Presented) A method as defined in claim 16, including the step of acquiring selected coating millages relating to said first film build process and selected coated millages relating to said second film build process; and

generating a cost difference between the first film build process and the second film build process utilizing the first Cpk and the second Cpk to ascertain the mean shift in Film Build millages.

20. (Previously Presented) A method as defined in claim 16, including the step of acquiring target range values relating to said first film build process and target range values relating to said second film build process; and

generating a cost difference between the first film build process and the second film build process utilizing the first C_{pk} and the second C_{pk}.

21. (Previously Presented) A method as defined in claim 16, including the step of acquiring data of the cost difference between the first and the second film build processes in which both of said film build processes have the same film thickness averages but with a different C_{pk} for the first and the second film build processes.

22. (Previously Presented) A method as defined in claim 16, including the step of acquiring data of the first film build process including Coating Minimum Specifications, Actual Film Thickness Average, Actual Film Thickness Range, the C_{pk} of the first film process, and a subgroup size.

23. (Previously Presented) A method as defined in claim 16, including the step of acquiring data regarding film build usage, of the first film build process and film build usage data of the second film build process, and in which the changed parameter is the film build material usage of said first film process, and then calculating the difference in film build material usage from the difference in the first C_{pk} value and the second C_{pk} value.

24. (Previously Presented) A method as defined in claim 16, in which the changed parameter is the process control limits of the second film_build process and then calculating the change in film build material usage from the difference in the first C_{pk} value and the second C_{pk} value.

25. (Previously Presented) A method as defined in claim 22, including the step of selecting target range values for the first film process and the second film process, and then calculating the differences in the film build material usage from the difference between the first C_{pk} value and the second value C_{pk}.

26. (Previously Presented) A method as defined in claim 16, including the step of acquiring data of the film build material usage of the first film build process, then selecting coating millages for at least one of said film build processes, and then calculating the change in film build material usage from the difference between said first C_{pk} value and the second C_{pk} value.

27. (Previously Presented) A method as defined in claim 16, including the step of acquiring data regarding the material usage values of the first film build process and the film usage of the second film build process based on using the same film thickness with different variability for the first and the second film build processes and then calculating the change in film build usage from the difference between said first C_{pk} value and the second C_{pk} value.

28. (Previously Presented) A method as defined in claim 16, including the step of calculating the optimal variability of the first film build process by adjusting the film millage average thereof, using said first C_{pk}, and in which optimal variability is defined as the lowest standard deviation in a run of seven or more units in the film build process.

29. (Previously Presented) A method as defined in claim 16, including the step of calculating the optimal variability of said first film build process by adjusting the film millage costs thereof utilizing said first C_{pk} and in which optimal variability is defined as the lowest standard deviation in a run of seven or more units in the build process.

30. (Previously Presented) A method as defined in claim 16, including the step of adjusting the variability of the first film build process to optimize the film millage average.

31. (Previously Presented) Apparatus for monitoring the film build thickness of workpieces on which a first film build process has been performed, comprising:

computer-implemented means for calculating a first C_{pk} of the workpieces on which the first film build process has been performed;

means for acquiring data relating to parameters of a second film build process in which at least one of the parameters thereof has been changed;

computer-implemented means for calculating a second C_{pk} of the second film build process; and

computer-implemented means for calculating the difference between the first C_{pk} and the second C_{pk} to develop a relationship between said difference and the changed parameter.